

Notice of References Cited	Application/Control No. 09/642,660	Applicant(s)/Patent Under Reexamination SCHNECK ET AL.	
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U.S. PATENT DOCUMENTS

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	N	WO 93/10220	5/1993		Selick et al	
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Zwirner J et al (J. Immunol. 1992 Jan;148(1):272-276)
	V	Kuwana et al (Biochem Biophys Res Commun 1987 Dec;149(3):960-968)
	W	Seimiya H et al (J Biochem (Tokyo) 1993 Jun;113(6):687-91)
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	N	WO 94/09131	4/1994		Harris et al	
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	U	Matsui et al (Proc. Natl. Acad. Sci., USA, 91(26)12862-12866, 20 December 1994)
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